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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/700,791	11/03/2003	Ernest Allen III	03-0724/LSI1P230	5486	
7590	08/24/2005		EXAMINER		
LSI Logic Corporation 1551 McCarthy Boulevard Milpitas, CA 95035		HOLLINGTON, JERMELE M			
		ART UNIT		PAPER NUMBER	
		2829			

DATE MAILED: 08/24/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

<b>Office Action Summary</b>	<b>Application No.</b>	<b>Applicant(s)</b>	
	10/700,791	ALLEN ET AL.	
	<b>Examiner</b> Jermele M. Hollington	<b>Art Unit</b> 2829	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

### Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

## Status

1)  Responsive to communication(s) filed on 14 June 2005.

2a)  This action is FINAL.                            2b)  This action is non-final.

3)  Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

## Disposition of Claims

4)  Claim(s) 1-17 and 19-24 is/are pending in the application.  
4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.

5)  Claim(s) 16, 17 and 19 is/are allowed.

6)  Claim(s) 1-9, 13-15, and 20-24 is/are rejected.

7)  Claim(s) 10-12 is/are objected to.

8)  Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

## Application Papers

9)  The specification is objected to by the Examiner.

10)  The drawing(s) filed on \_\_\_\_\_ is/are: a)  accepted or b)  objected to by the Examiner.

Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).

11)  The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

12)  Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).  
a)  All · b)  Some \* c)  None of:  
1.  Certified copies of the priority documents have been received.  
2.  Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.  
3.  Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

**Attachment(s)**

1)  Notice of References Cited (PTO-892)  
2)  Notice of Draftsperson's Patent Drawing Review (PTO-948)  
3)  Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  
Paper No(s)/Mail Date . . . . .  
4)  Interview Summary (PTO-413)  
Paper No(s)/Mail Date. . . . .  
5)  Notice of Informal Patent Application (PTO-152)  
6)  Other: . . . . .

## DETAILED ACTION

1. Applicant's arguments with respect to claims 1-19 have been considered but are moot in view of the new ground(s) of rejection.
2. The indicated allowability of claims 5-6, and 15 is withdrawn in view of the discovered portion of the reference(s). Rejections based on the cited reference(s) follow.

### *Claim Objections*

3. Claims 5-6 are objected to under 37 CFR 1.75(c), as being of improper dependent form for failing to further limit the subject matter of a previous claim. Applicant is required to cancel the claim(s), or amend the claim(s) to place the claim(s) in proper dependent form. The limitations in claims 5-6 are included in the amending claim 1, which both claims depend off of.

### *Claim Rejections - 35 USC § 102*

4. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

5. Claims 1-4, 8-9, 13-14 and 16-17 are rejected under 35 U.S.C. 102(b) as being anticipated by Kalb, Jr. (5742177).

Regarding claims 1 and 15, Kalb, Jr. discloses a method for testing a semiconductor device [see Abstract], the method comprising: measuring [see steps 410 and 420 in Fig. 4] for a first semiconductor device a first current (IDQ1) at a first voltage (V1) and a second current (IDQ2) at a second Voltage (V2) [see col. 6, lines 13-18]; identifying the functional relationship (temperature and/or voltage) between the first (IDQ1) and second currents

(IDDQ2); and comparing [see steps 440-442] the functional relationship (temperature and/or voltage) to a predetermined relationship to determine whether the device is defective [see col. 6, lines 19-23] wherein inherently [see below] the predetermined relationship (via screen condition) is determined [via screen condition see col. 6, lines 24-34].

Although the prior art does not specifically disclose the claimed “predetermined relationship is determined by at least one of evaluating the function relationship for at least one other die on the same wafer or is determined from a plurality of dies fabricated previously and comprises a running average,” this feature is seen to be an inherent teaching of that device since a particular user can set a screen condition that is used as a threshold tolerance for a defective device is disclosed and it is apparent that some type of predetermined relationship must be presented for the semiconductor device testing to function as intended.

Regarding claim 2, Kalb, Jr. discloses the functional relationship (temperature and/or voltage) is a ratio between the first and second currents [see col. 4, line 52-col. 6, line 11].

Regarding claims 3-4, Kalb, Jr. discloses the first semiconductor device is a transistor or an integrated circuit.

Regarding claim 8, Kalb, Jr. discloses the first (IDDQ1) and second (IDDQ2) currents are quiescent currents [see col. 6, lines 13-18].

Regarding claim 9, Kalb, Jr. discloses the device is determined [see steps 440-442] to be defective if it deviates from the predetermined relationship by a predetermined threshold [see col. 6, lines 24-34].

Regarding claims 13-14, Kalb, Jr. discloses the first (IDDQ1) and second (IDDQ2) currents are supplied and measured by automated test equipment [not shown].

Regarding claim 20, Kalb, Jr. discloses a method for testing a semiconductor device [see Abstract], the method comprising: measuring [see steps 410 and 420 in Fig. 4] for a first semiconductor device a first current (IDQ1) at a first voltage (V1) and a second current (IDQ2) at a second Voltage (V2) [see col. 6, lines 13-18]; identifying the functional relationship (temperature and/or voltage) between the first (IDQ1) and second currents (IDQ2); and comparing [see steps 440-442] the functional relationship (temperature and/or voltage) to a predetermined relationship (via screen condition) to determine whether the device is defective [see col. 6, lines 19-23].

Regarding claims 21 and 23, Kalb, Jr. discloses the predetermined reference (via screen condition) comprises an expected functional relationship between said first (IDQ1) and second (IDQ2) currents [see below].

Although the prior art does not specifically disclose the claimed “predetermined reference is determined by at least one: a measurement of a prototype chip or characterization of a history of similar chips already fabricated,” this feature is seen to be an inherent teaching of that device since a particular user can set a screen condition that is used as a threshold tolerance for a defective device is disclosed and it is apparent that some type of predetermined reference must be presented for the semiconductor device testing to function as intended.

Regarding claim 22, Kalb, Jr. discloses the predetermined reference (via screen condition) is related to an ohmic linear relationship defined by the ratio the first current (IDQ1) at high Vdd and the second current (IDQ2) at low Vdd.

Regarding claim 24, Kalb, Jr. discloses a method for testing a semiconductor device [see Abstract], the method comprising: measuring [see steps 410 and 420 in Fig. 4] for a first

semiconductor device a first current (IDQ1) at a first voltage (V1) and a second current (IDQ2) at a second Voltage (V2) [see col. 6, lines 13-18]; identifying the functional relationship (temperature and/or voltage) between the first (IDQ1) and second currents (IDQ2); and comparing [see steps 440-442] the functional relationship (temperature and/or voltage) to a predetermined relationship to determine whether the device is defective [see col. 6, lines 19-23] wherein inherently [see below] the predetermined relationship (via screen condition) is determined [via screen condition see col. 6, lines 24-34].

Although the prior art does not specifically disclose the claimed “predetermined relationship comprises a running average,” this feature is seen to be an inherent teaching of that device since a particular user can set a screen condition that is used as a threshold tolerance for a defective device is disclosed and it is apparent that some type of predetermined relationship must be presented for the semiconductor device testing to function as intended.

***Claim Rejections - 35 USC § 103***

6. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

7. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out

the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

8. Claims 7 and 19 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kalb, Jr. (5742177) in view of Miller (6239606).

Regarding claims 7 and 19, Kalb, Jr. discloses a method for testing a semiconductor device [see Abstract], the method comprising: measuring [see steps 410 and 420 in Fig. 4] for a first semiconductor device a first current (IDQ1) at a first voltage (V1) and a second current (IDQ2) at a second Voltage (V2) [see col. 6, lines 13-18]; identifying the functional relationship (temperature and/or voltage) between the first (IDQ1) and second currents (IDQ2); and comparing [see steps 440-442] the functional relationship (temperature and/or voltage) to a predetermined relationship to determine whether the device is defective [see col. 6, lines 19-23]. However, he does not disclose measuring a third current at a third voltage as claimed. Miller disclose a method for testing a semiconductor device [see Abstract], the method comprising: measuring [see steps 600, 604 and 608 in Fig. 6] for a first semiconductor device a first current (first quiescent current) at a first voltage, a second current (second quiescent current) at a second voltage and a third current (third quiescent current) at a third voltage [see col. 6, lines 3-9]; and comparing [see steps 610] the functional relationship to a predetermined relationship to determine whether the device is defective [see col. 6, lines 12-16]. Further, Miller teaches that the addition of measuring a third current is advantageous because it may be found to fail only those devices wherein a defect is detected two or more times in the event that the first detection was an error or is not repeatable. It would have been obvious to a person having

ordinary skill in the art at the time the invention was made to modify the apparatus of Kalb, Jr. by adding a third current measuring as taught by Miller in order to failed only those devices wherein a defect is detected two or more times in the event that the first detection was an error or is not repeatable.

*Conclusion*

**Allowable Subject Matter**

1. Claims 10-12, 15 and 18 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
2. Claims 16-17 and 19 are allowed.
3. The following is a statement of reasons for the indication of allowable subject matter: regarding claim 10, the primary reason for the allowance of the claim is due to method for testing a semiconductor device comprising the functional relationship is a ratio of the first and second currents and the predetermined threshold is about 20 % of the value determined for the ratio.

Regarding claim 11, the primary reason for the allowance of the claim is due to method for testing a semiconductor device comprising the first and second voltages are set within the range from 50 to 140 % of a nominal supply voltage for the device.

Regarding claim 12, the primary reason for the allowance of the claim is due to method for testing a semiconductor device comprising the first and second voltages are set within the range from 60 to 120 % of a nominal supply voltage for the device.

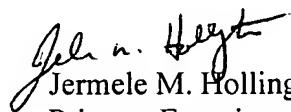
Regarding claim 16, the primary reason for the allowance of the claim is due to amending the claim to add the allowable limitation of claim 18 that states a semiconductor device

comprising the first and second voltages are set within the range from 50 to 140 % of a nominal supply voltage for the device. Since claims 17 and 19 depend off of claim 16, they also have allowable subject matter.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jermele M. Hollington whose telephone number is (571) 272-1960. The examiner can normally be reached on M-F (9:00-4:30 EST) First Friday Off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nestor Ramirez can be reached on (517) 272-2034. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

  
Jermele M. Hollington  
Primary Examiner  
Art Unit 2829

JMH  
August 19, 2005